

FORM PTO-1449
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
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APPLICATION NO

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LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Heinrich ULRICH et al.

FILING DATE

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GROUP 2877

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
/FLE/	A01	2003/058530 A1	Mar. 27, 2003	Kawano 2003/0058530	359	385	
/FLE/	A02	6,255,642 B1	Jul. 3, 2001	Cragg et al.	250	216	
/FLE/	A03	2002/0097489 A1	Jul. 25, 2002	Kawano et al.	359	388	
	A04						
	A05						
	A06						
	A07						
	A08						
	A09						
	A10						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION
							YES NO
/FLE/	A11	DE 199 02 234 A1	Feb. 24, 2000	DE-Germany			See Intl. Search Report for PCT/EP2004/052296; see English Abstract
	A12						
	A13						
	A14						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

/FLE/	A15	V. Protasenko et al.: "Enhancement and quenching of the fluorescence of single CdSe/ZnS quantum dots studied by confocal apertureless near-field scanning optical microscope"; Proceedings of SPIE Vol. 5188 Advanced Characterization Techniques for Optics, Semiconductors, and Nanotechnologies, November 2003, pp. 254-263
↓	A16	S. Kawata et al.: "Near-Field Scanning Optical Microscope with a Laser Trapped Probe"; Jpn. J. Appl. Phys. Vol. 33 (1994), Part 2, No. 12A, 1 December 1994, pp. L 1725-L 1727
/FLE/	A17	International Search Report for PCT/EP2004/052296 (3 pages)
	A18	
	A19	
	A20	

EXAMINER

/F. L. Evans/

DATE CONSIDERED

03/07/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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10/15/08
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